Abstracts

Novel MMIC source-impedance tuners for on-wafer microwave noise-parameter measurements

C.E. McIntosh, R.D. Pollard and R.E. Miles. "Novel MMIC source-impedance tuners for on-wafer microwave noise-parameter measurements." 1999 Transactions on Microwave Theory and Techniques 47.2 (Feb. 1999 [T-MTT]): 125-131.

Novel monolithic-microwave integrated-circuit source-impedance tuners for use in on-wafer noise-parameter measurement systems are reported, which can be incorporated into a wafer probe tip. These eliminate the effect of cable and probe losses on the magnitude of a reflection coefficient that can be presented to the input of an on-wafer test device, thus enabling higher magnitudes to be synthesized than for conventional tuners, and with the potential of increasing noise-parameter measurement accuracy.

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